

Test Report

No. 1-1587-25-01-05_TR1-R01

February 05. 2026

Applicant	LID Technologies
Product	Smart Diag Box 434MHz
Model	21125
Tested Technology	Proprietary
Test Standard	FCC 47 CFR Part 2

Verdict **TEST EXEMPTION FULFILLED**

The test results apply only to the equipment specified in this document.

This test report is electronically signed and valid without handwritten signature.
Public keys for verification of the electronic signatures can be requested at the testing laboratory.

authorized by

Alexander Hnatovski

Coordinator Area
Regulatory Services Radio

created by

Eric Tuettmann

Testing Manager
Regulatory Services Radio

Table of Contents

1. Disclaimer	3
2. Related cetecom advanced documents	4
3. Document history	5
3.1. Current release	5
3.2. Previous releases	5
4. Test laboratory	6
4.1. Contact information	6
4.2. Involved test locations	6
4.3. Subcontracted laboratories	6
4.4. Laboratory listings and recognitions	6
5. Client information	7
5.1. Applicant	7
5.2. Manufacturer	7
6. Test sample information	8
6.1. General Information	8
6.1.1. General Data of Main EUT as Declared by Applicant	8
7. Measurement details	9
7.1. Test methodology	9
8. SAR test exclusion (KDB 447498 D01 General RF Exposure Guidance v06)	10
8.0.1. 4.3.1. Standalone SAR test exclusion considerations	10
8.0.2. Results	12

1. Disclaimer

The test results of this test report relate exclusively to the test item specified in chapter "Test sample information". cetecom advanced does not assume responsibility for any conclusions and generalizations drawn from the test results regarding other specimens or samples of the type of the equipment represented by the test item.

The test report may only be reproduced or published in full. Reproduction or publication of extracts from the report requires the prior written approval of cetecom advanced.

The testing service provided by cetecom advanced has been rendered under the current "General Terms and Conditions for cetecom advanced".

cetecom advanced will not be liable for any loss or damage resulting from false, inaccurate, inappropriate, or incomplete product information provided by the customer.

Under no circumstances does the cetecom advanced test report include any endorsement or warranty regarding the functionality, quality or performance of any other product or service provided.

Under no circumstances does the cetecom advanced test report include or imply any product or service warranties from cetecom advanced, including, without limitation, any implied warranties of merchantability, fitness for purpose, or non-infringement, all of which are expressly disclaimed by cetecom advanced.

All rights and remedies regarding vendor's products and services for which cetecom advanced has prepared this test report shall be provided by the party offering such products or services and not by cetecom advanced. In no case this test report can be considered as a Letter of Approval.

This test report is electronically signed and valid without handwritten signature. Public keys for verification of the electronic signatures can be requested at the testing laboratory.

The test report must always be reproduced in full; reproduction of an excerpt only is subject to written approval of the testing laboratory. The documentation of the testing performed on the tested devices is archived for 10 years at cetecom advanced.

2. Related cetecom advanced documents

Title	Description	Reference	Total Pages
n/a			

3. Document history

3.1. Current release

Release No.: R01
Date of release: February 05. 2026
Applied changes: Initial release

3.2. Previous releases

Version	Applied change	Date of release
n/a		

4. Test laboratory

4.1. Contact information

cetecom advanced GmbH
Untertuerkheimer Str. 6-10
66117 Saarbruecken
Germany

4.2. Involved test locations

Saarbrücken Lab

Untertürkheimer Strasse 6 – 10
66117 Saarbrücken
Germany

4.3. Subcontracted laboratories

None.

4.4. Laboratory listings and recognitions

	Saarbrücken	Essen
FCC	DE0002	DE0003
ISED	DE0001 3462C	DE0001 3462D

5. Client information

5.1. Applicant

Name: LID Technologies
Address: FRANCE, 31520 Ramonville Saint Agne, 12 rue Hermès - Bâtiment C
Contact Person: Olivier Dobigeon
Contact Person's Email: odobigeon@lid.tech

5.2. Manufacturer

Name: LID Technologies
Address: FRANCE, 31520 Ramonville Saint Agne, 12 rue Hermès - Bâtiment C
Contact Person: Olivier Dobigeon
Contact Person's Email: odobigeon@lid.tech

6. Test sample information

The data about the test samples is given/supplied by the customer and not under control by cetecom advanced GmbH.

6.1. General Information

6.1.1. General Data of Main EUT as Declared by Applicant

FCC ID	T4521125
Antenna	Integrated Antenna

7. Measurement details

7.1. Test methodology

Test method, standard, rule	Description
FCC 47 CFR Part 2	Federal Communications Commission, 47 code of federal regulations, Part 2: General Rules & Regulations for Equipment Authorisation

8. SAR test exclusion (KDB 447498 D01 General RF Exposure Guidance v06)

8.0.1. 4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Test Exclusion Threshold condition(s), listed below, is (are) satisfied. These test exclusion conditions are based on source-based time-averaged maximum conducted output power of the RF channel requiring evaluation, adjusted for tune-up tolerance, and the minimum test separation distance required for the exposure conditions. The minimum test separation distance defined in 4.1 f) is determined by the smallest distance from the antenna and radiating structures or outer surface of the device, according to the host form factor, exposure conditions and platform requirements, to any part of the body or extremity of a user or bystander. To qualify for SAR test exclusion, the test separation distances applied must be fully explained and justified, typically in the SAR measurement or SAR analysis report, by the operating configurations and exposure conditions of the transmitter and applicable host platform requirements, according to the required published RF exposure KDB procedures. When no other RF exposure testing or reporting are required, a statement of justification and compliance must be included in the equipment approval, in lieu of the SAR report, to qualify for SAR test exclusion. When required, the device specific conditions described in the other published RF exposure KDB procedures must be satisfied before applying these SAR test exclusion provisions; for example, handheld PTT two-way radios, handsets, laptops and tablets, etc.

a) For 100 MHz to 6 GHz and test separation distances ≤ 50 mm, the 1-g and 10-g SAR test exclusion thresholds are determined by the following:

$$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f_{\text{(GHz)}}}] \leq 3.0$$
 for 1-g SAR, and ≤ 7.5 for 10-g extremity SAR, where

$f_{\text{(GHz)}}$ is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation

The result is rounded to one decimal place for comparison

The values 3.0 and 7.5 are referred to as numeric thresholds instep b) below

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm, and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm according to 4.1 f) is applied to determine SAR test exclusion.

b) For 100 MHz to 6 GHz and test separation distances > 50 mm, the 1-g and 10-g SAR test exclusion thresholds are determined by the following:

1) $\{[\text{Power allowed at numeric threshold for 50 mm in step a)}] + [(\text{test separation distance}$

$- 50 \text{ mm}) \cdot (f_{\text{(MHz)}}/150)]\}$ mW, for 100 MHz to 1500 MHz

2) $\{[\text{Power allowed at numeric threshold for 50 mm in step a)}] + [(\text{test separation distance} - 50 \text{ mm}) \cdot 10]\}$ mW, for > 1500 MHz and ≤ 6 GHz

c) For frequencies below 100MHz, the following may be considered for SAR test exclusion(also illustrated in AppendixC):

For test separation distances > 50 mm and < 200 mm, the power threshold at the corresponding test separation distance at 100 MHz in step b) is multiplied by $[1 + \log(100/f_{\text{(MHz)}})]$

For test separation distances ≤ 50 mm, the power threshold determined by the equation in c) 1) for 50mm and

100 MHz is multiplied by $\frac{1}{2}$

SAR measurement procedures are not established below 100 MHz.

MHz	5	10	15	20	25	mm
150	49	77	116	155	194	
300	27	55	82	110	137	
450	22	45	67	89	112	
835	16	33	49	66	82	
900	16	32	47	63	79	
1500	12	24	37	49	61	
1900	11	22	33	44	54	
2450	10	19	29	38	48	
3600	8	16	24	32	40	
5200	7	13	20	26	33	
5400	6	13	19	26	32	
5800	6	12	19	25	31	

8.0.2. Results

customer declared minimum safety distance: 199 mm

Technology	Note	Frequency [MHz]	Threshold 1g, 10g	Threshold 100 MHz, 199mm	Powerlimit [mW]	P _{max} [dBm]	P _{max} [mW]	Limit [%]
Proprietary	A	0.125	3	13416.41	2239.11	13.43	22.03	0.98

Technology	Note	Frequency [MHz]	Threshold 1g	Powerlimit [mW]	P _{max} [dBm]	P _{max} [mW]	Limit [%]
Proprietary	B	433.00	3	907.26	-0.53	0.89	0.10%

Technology	Share of Limit
Proprietary	0.10%
Proprietary	0.98%
Sum	1.08%

Notes & References

#	Document	Document Type	Additional Information
A	-/-	Module Datasheet	5.5V max Voltage, 4mA max Amperage= 22 mW
B	1-1587-25-01-02_TR1-R01	cetecom advanced report	Pg. 24, Field strength of Fundamental

End of document